

## Dual N-Channel 30-V (D-S) MOSFET

### CHARACTERISTICS

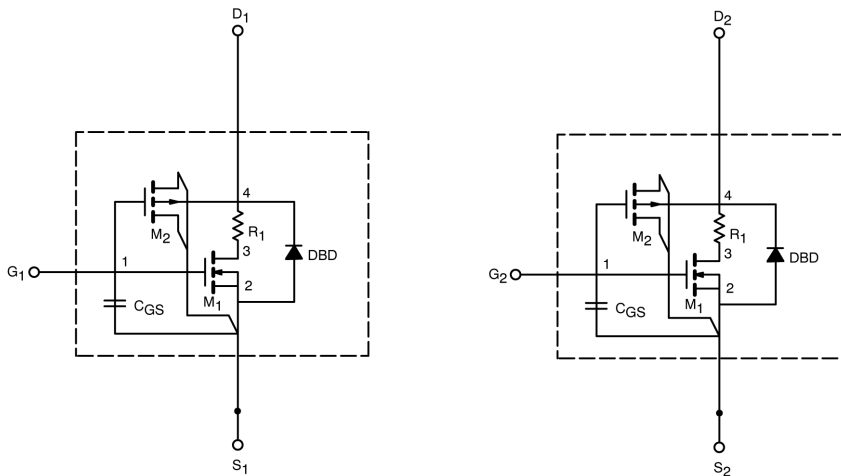
- N-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the  $-55$  to  $125^{\circ}\text{C}$  Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

### DESCRIPTION

The attached spice model describes the typical electrical characteristics of the n-channel vertical DMOS. The subcircuit model schematic is extracted and optimized over the  $-55$  to  $125^{\circ}\text{C}$  temperature ranges under the pulsed 0-to-5V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched  $C_{gd}$  model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

### SUBCIRCUIT MODEL SCHEMATIC



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.

# SPICE Device Model Si9936DY

Vishay Siliconix



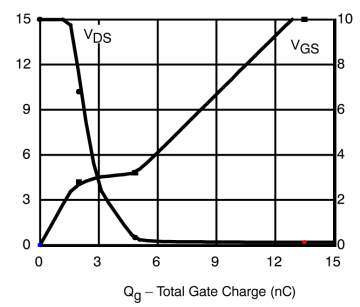
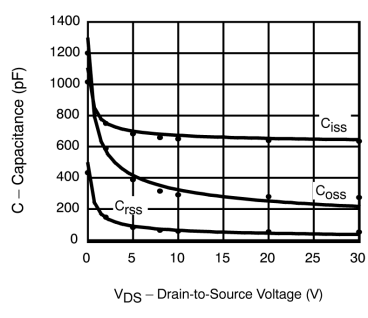
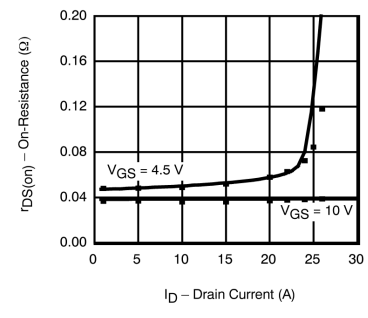
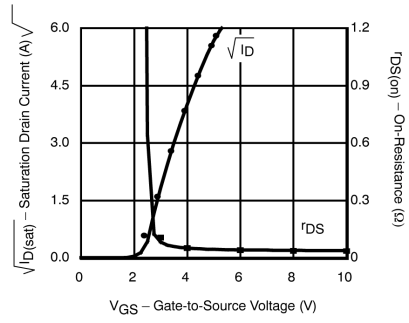
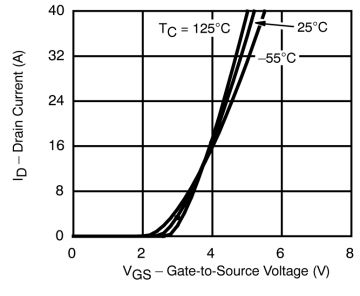
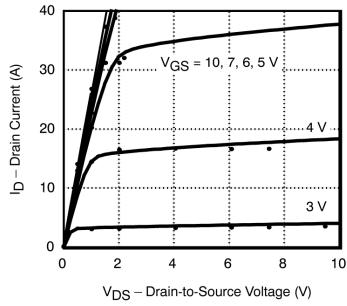
SPECIFICATIONS ( $T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)				
Parameter	Symbol	Test Condition	Typical	Unit
<b>Static</b>				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.77	V
On-State Drain Current <sup>a</sup>	$I_{D(on)}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	120	A
Drain-Source On-State Resistance <sup>a</sup>	$r_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 5.0 \text{ A}$	0.038	$\Omega$
		$V_{GS} = 4.5 \text{ V}, I_D = 3.9 \text{ A}$	0.049	
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 5 \text{ A}$	11	S
Diode Forward Voltage <sup>a</sup>	$V_{SD}$	$I_S = 1.7 \text{ A}, V_{GS} = 0 \text{ V}$	0.72	V
<b>Dynamic<sup>b</sup></b>				
Total Gate Charge <sup>b</sup>	$Q_g$	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$	13	nC
Gate-Source Charge <sup>b</sup>	$Q_{gs}$		1.9	
Gate-Drain Charge <sup>b</sup>	$Q_{gd}$		3	
Turn-On Delay Time <sup>b</sup>	$t_{d(on)}$	$V_{DD} = 15 \text{ V}, R_L = 15 \Omega$ $I_D \cong 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 6 \Omega$	8	ns
Rise Time <sup>b</sup>	$t_r$		10	
Turn-Off Delay Time <sup>b</sup>	$t_{d(off)}$		24	
Fall Time <sup>b</sup>	$t_f$		37	
Source-Drain Reverse Recovery Time	$t_{rr}$	$I_F = 1.7 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$	62	

**Notes**

- a. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .
- b. Guaranteed by design, not subject to production testing.



**COMPARISON OF MODEL WITH MEASURED DATA ( $T_J=25^\circ\text{C}$  UNLESS OTHERWISE NOTED)**



Note: Dots and squares represent measured data.